



Advanced Technology Related to Radar Signal, Imaging, and Radar Cross-Section Measurement, Volume II

Guest Editors:

Prof. Dr. Hirokazu Kobayashi

Department of Electronics and Information Systems Engineering, Osaka Institute of Technology, Osaka 535-8585, Japan

Prof. Dr. Toshifumi Moriyama

Graduate School of Engineering, Nagasaki University, 1-14 Bunkyo-machi, Nagasaki 852-8521, Japan

Deadline for manuscript submissions:

closed (15 September 2024)

Message from the Guest Editors

The aim of this Special Issue of Electronics is to present state-of-the-art investigations in various radar-important technologies for future applications. We invite researchers to contribute original and unique articles, as well as sophisticated review articles. Topics include, but are not limited to, the following areas:

- Radar imaging technology.
- Inverse synthetic aperture radar imaging.
- Inverse electromagnetic scattering.
- Short-distance radar.
- Collision-avoidance radar.
- Subsurface and ground penetrating radar.
- Microwave remote sensing image analysis.
- RCS near-field to far-field transformation.
- Radar electromagnetic modeling and simulation.
- Target recognition.
- Radar data fusion.





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.

Journal Rank: JCR - Q2 (*Physics, Applied*) / CiteScore - Q2 (*Control and Systems Engineering*)

Contact Us

Electronics Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/electronics
electronics@mdpi.com
[X@electronicsMDPI](https://x.com/electronicsMDPI)